

Notice of References Cited	Application/Control No. 10/528,570	Applicant(s)/Patent Under Reexamination OGAWA ET AL.	
	Examiner Maureen M. Wallenhorst	Art Unit 1743	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,641,622	06-1997	Lake et al.	435/2
*	B	US-2005/0026301	02-2005	Petithory, Henry	436/180
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2002-267677	09-2002	JP	Horiike et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Oki et al. Japanese Journal of Applied Physics, vol. 42, pt. 1, no. 6A, June 2003, pages 3722-3727.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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